

**METHODS AND APPARATUS FOR ANALYZING FLUTTER TEST DATA USING  
DAMPED SINE CURVE FITTING**

**ABSTRACT OF THE DISCLOSURE**

5           Methods and apparatus for analyzing of flutter test data using damped sine curve  
fitting are provided. A plurality of data points are read, with each data point representing an  
amplitude versus a test time. A number "N" of damped sine waves to fit to the plurality of  
data points is determined, and the number "N" of damped sine waves is fit to the plurality of  
10 data points using a non-linear "N" damped sine wave fitting algorithm.



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